



# Evolution of pulsed current and carrier lifetime characteristics in Si structures during 25 MeV neutrons irradiation using spallator type neutrons source

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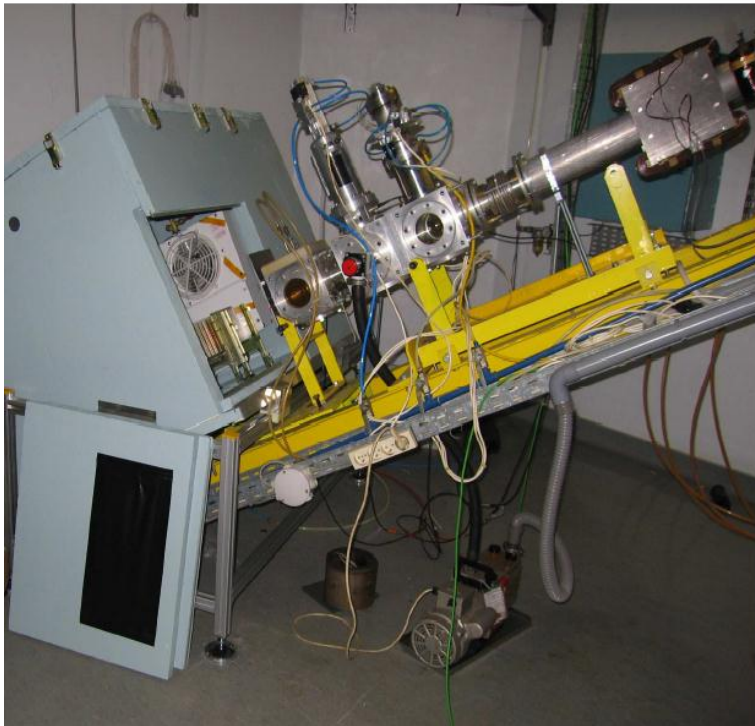
## Outline

- Motivation
- Neutron source at Louvain la Neuve University
- Sketch of experiments
- Evolution of the pulsed currents and carrier recombination characteristics
- Summary

## Motivation

- To predict signal changes and to foresee possible modifications of the detector performance
- Comparison of variations of carrier drift and recombination characteristics during neutron and proton irradiations

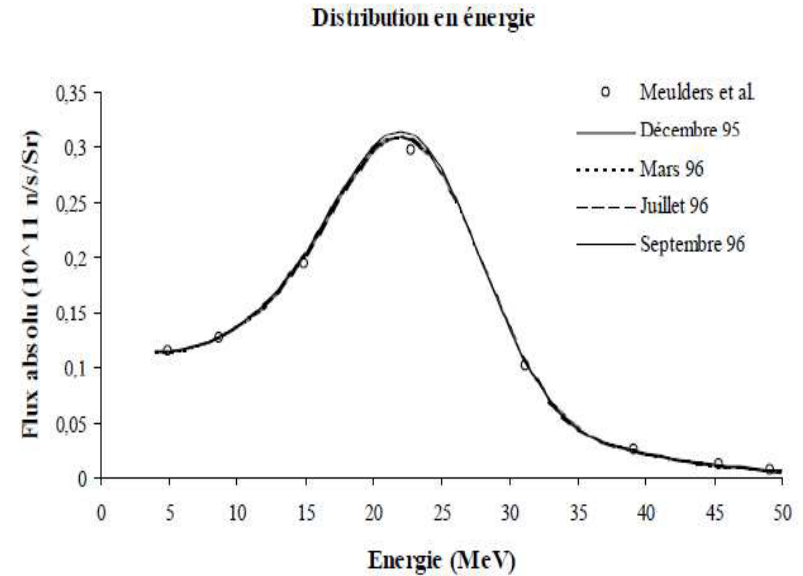
# Neutron source at Louvain la Neuve University



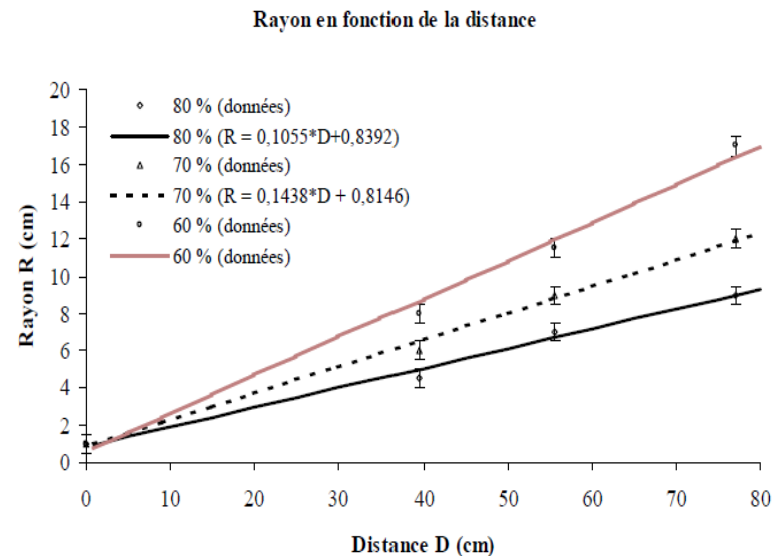
The high flux neutron line is located at the Louvain la Neuve -Cyclotron. It uses a primary 50 MeV deuteron beam that is sent on a thin beryllium target. The high cross section reaction  ${}^9\text{Be}(d,n){}^{10}\text{B}$  produces the high flux neutron beam.

To keep the gamma and charged particle contamination as low as possible filters are placed outside the target box and fixed to the box window, made of three layers: 1 cm thick polyethylene, 1 mm Cadmium and 1 mm Lead. The filter also removes from the beam the low energy neutrons.

The energy spectrum of the out-coming neutron beam is dominated by a peak in the region of 25 MeV.

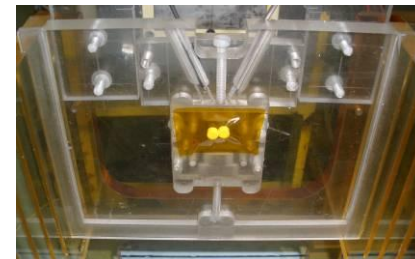


## Neutron spatial distribution variation with distance from the target



# Sketch of experiments

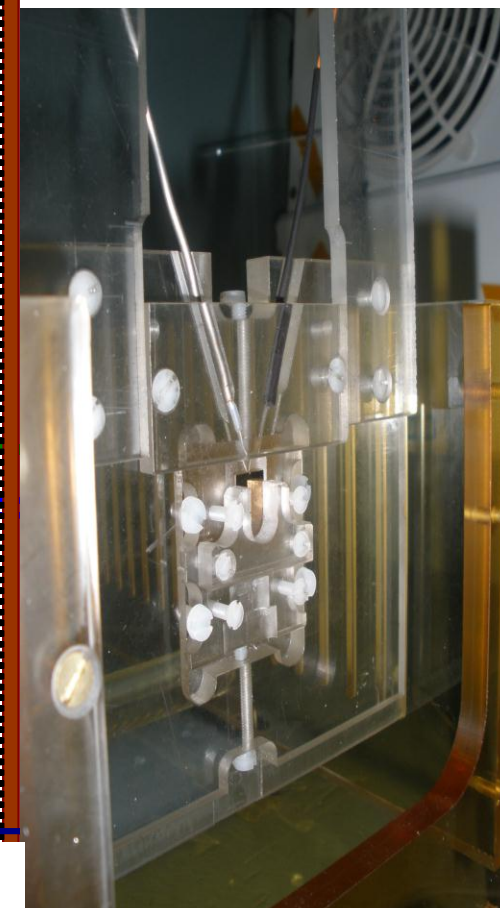
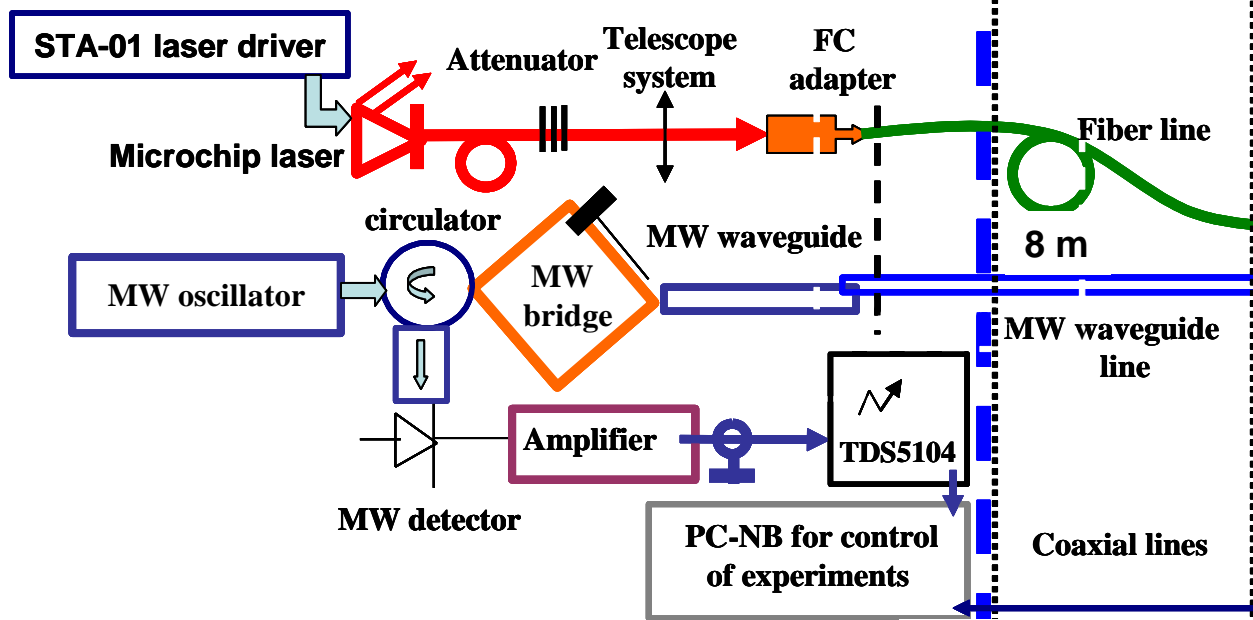
## MW-PC measurement setup



VUTEG-3

①

②

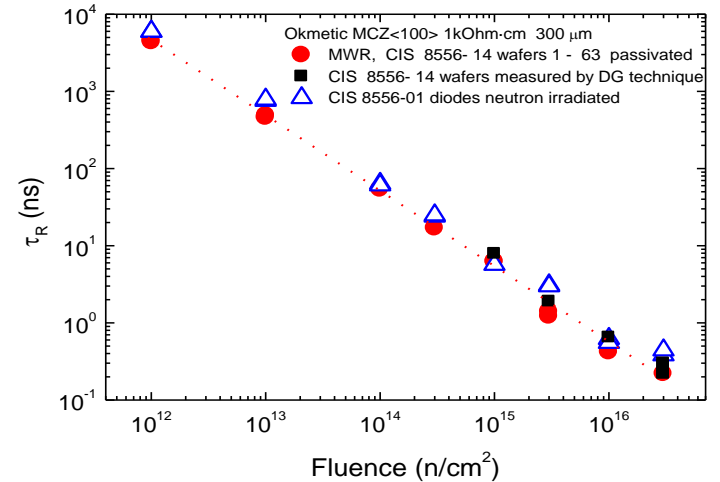
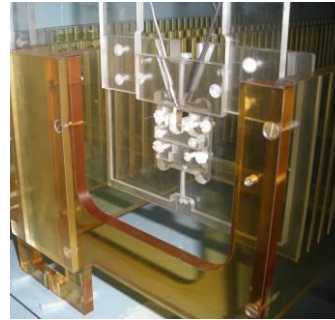


# Comparison of results of the in situ changes of recombination lifetime during 8 MeV protons, nuclear reactor and spallator 25 MeV neutrons irradiation

## Reactor neutrons

$$\tau_{R,cluster} = \frac{1}{v_T \sigma_{cl} N_{cl}} = \frac{1}{v_T \sigma_{cl}(\Phi)(N_{cl,0} + N_{cl}(\Phi))}$$

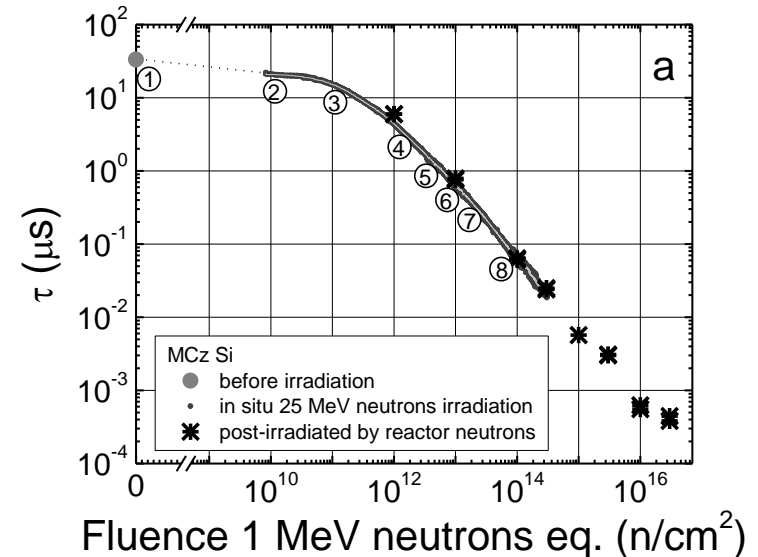
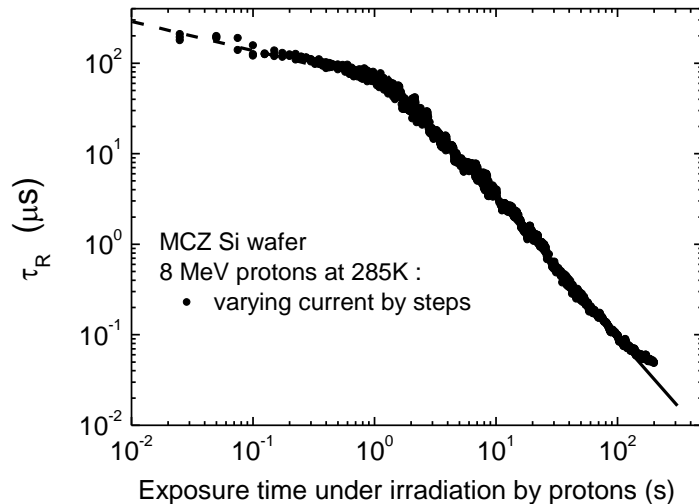
$$\sigma_{cl} = \sigma_0 \exp(eV_{b,cl} / kT)$$



$$\tau_{R,cluster} \cong \frac{1}{v_T \sigma_0 \left[ \frac{N_D}{n_i^2} \left( \sum_{n=1}^{V_n} \frac{\partial N_{A,n}}{\partial \Phi} \Phi \right) (N_{cl,0} + \frac{\partial N_{cl}(\Phi)}{\partial \Phi} \Phi) \right]^c} \propto \frac{1}{a\Phi^c + b\Phi^{c+1}}$$

## 8 MeV protons

## Spallator neutrons



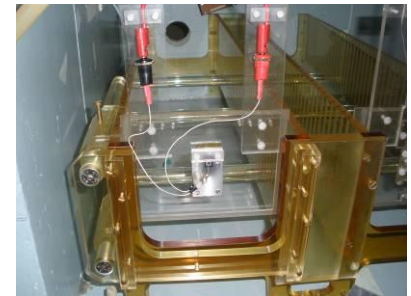
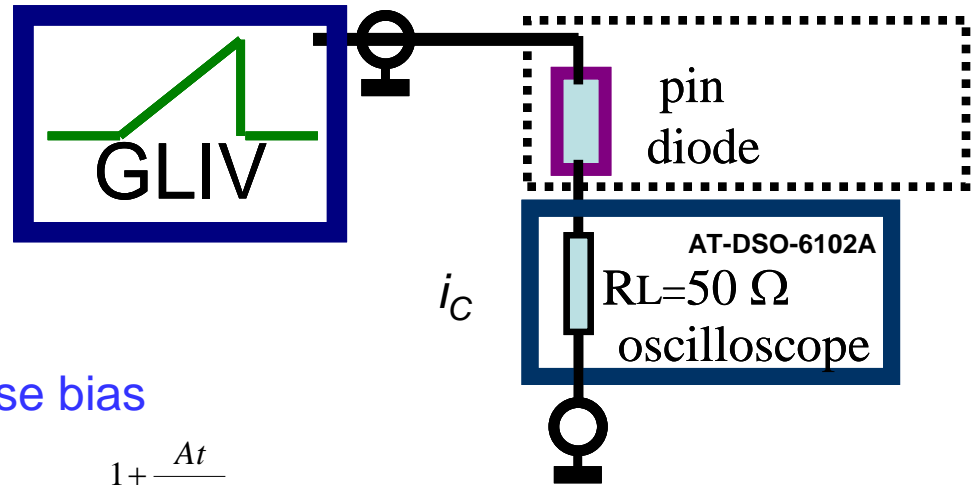
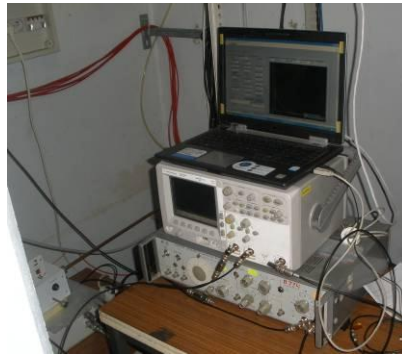
# Setup for implementation of BELIV technique

$$U(t) = U_p / \tau_{PL} t = At$$

$$\text{LIV ramp } A = U_p / \tau_{PL} = \partial U / \partial t$$

$$\tau_{PL} = 10 \text{ ns} \Rightarrow 500 \mu\text{s}$$

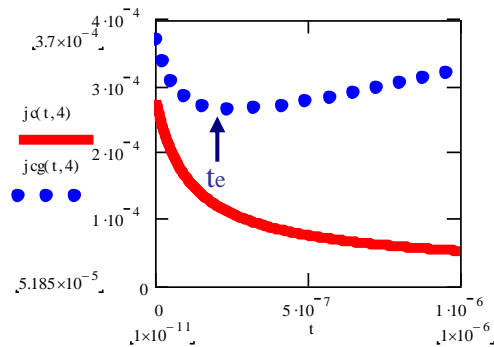
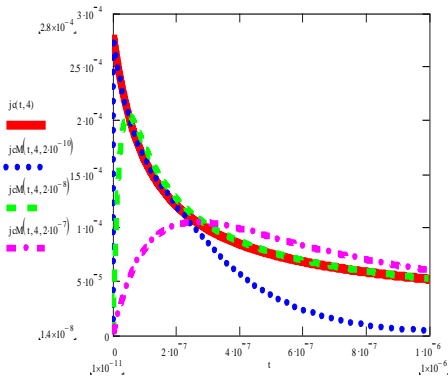
$$U_p = 0.01 \Rightarrow 5 \text{ V}$$



## Reverse bias

$$i_C(t) = \frac{dq}{dt} = AC_{b0} \frac{1 + \frac{At}{2U_{bi}}}{\left(1 + \frac{At}{U_{bi}}\right)^{3/2}}$$

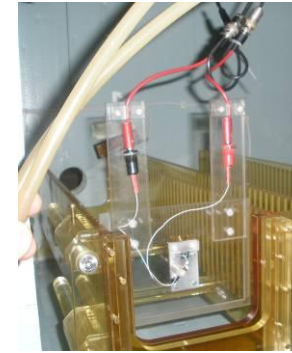
$$i_{CM}(t) = \frac{1}{\tau_{RC}} \int_0^t i_C(x) \exp\left[-\frac{(t-x)}{\tau_{RC}}\right] dx$$



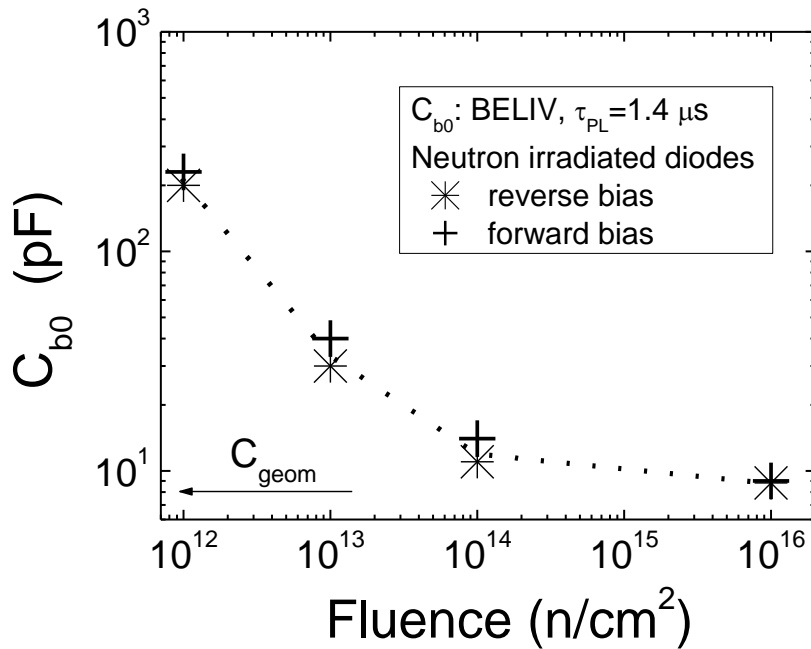
$$i_{R\Sigma}(t) = i_C(t) + i_{diff}(t) + i_g(t) = AC_{b0} \frac{1 + \frac{At}{2U_{bi}}}{\left(1 + \frac{At}{U_{bi}}\right)^{3/2}} + i_{diff\infty} \left(1 - e^{-\frac{eAt}{kBT}}\right) + \frac{emS\omega_0}{\tau_g} \left(1 + \frac{At}{U_{bi}}\right)^{1/2}$$

$$t_e = \frac{U_{bi}}{Ai_g(0)} \left[ \frac{i_C(0)}{4} - i_g(0) + \sqrt{\left(\frac{i_C(0)}{4}\right)^2 + \frac{3}{2} i_C(0) i_g(0)} \right]$$

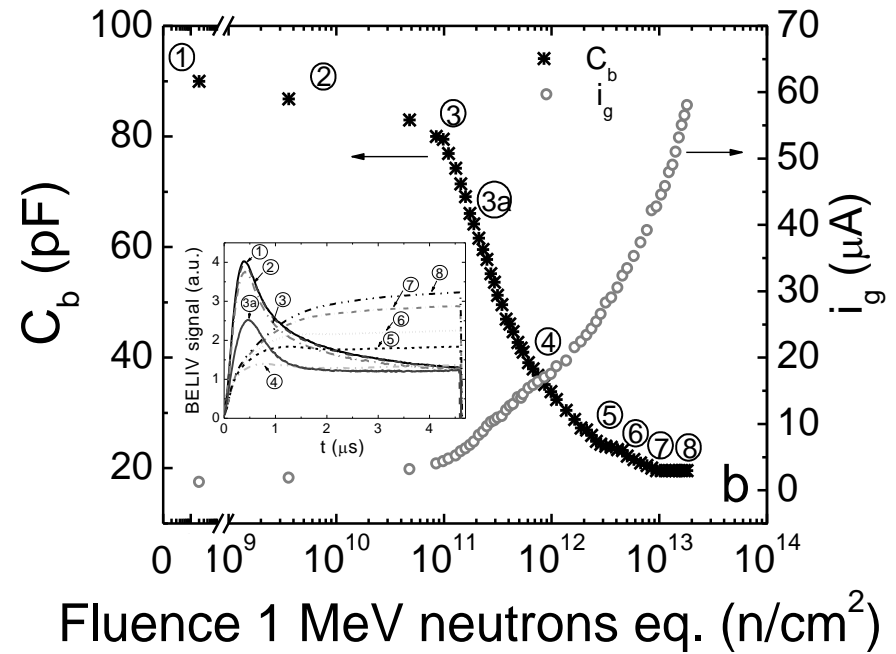
**Comparison of results** of changes of the barrier capacitance charging and thermal-generation current changes under nuclear reactor and spallator 25 MeV neutrons irradiation, measured in situ by BELIV technique



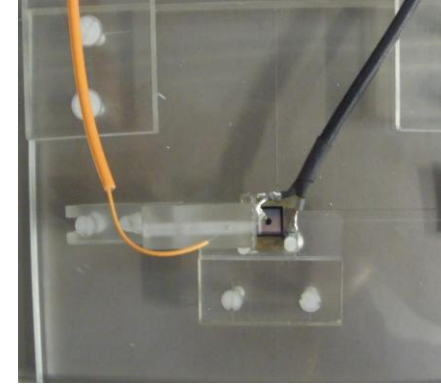
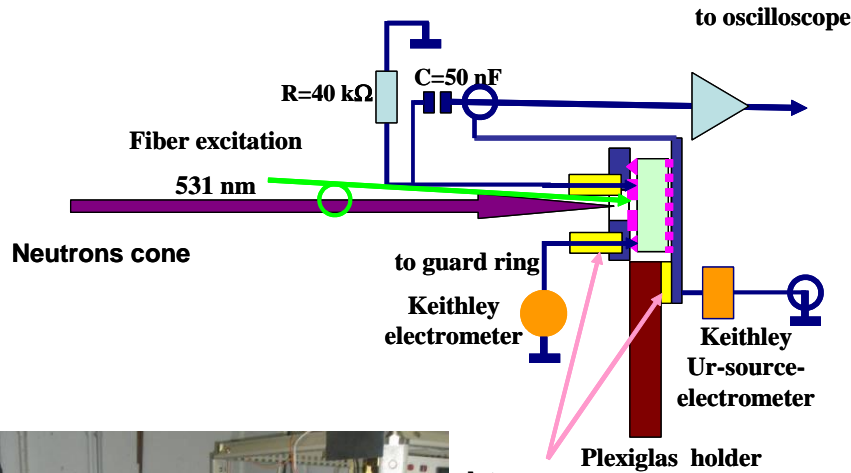
## Reactor neutrons



## Spallator neutrons



# ICDC- induced surface charge domain drift currents: measurement setup



$$U > U_{FD}$$

$$j(t) = q(t) \frac{dy}{dt} + \frac{q(t)}{\tau_R} [1 - y(t)] + \frac{ed}{2} \frac{dm}{dt}$$

$$v(y) = d \frac{dy}{dt}$$

$$dy/dt - [\tau_m^{-1}(t) + \tau_q^{-1}(t) - \tau_{Ndef}^{-1}] y(t) - [\tau_{dr}^{-1} - \tau_m^{-1}(t)] = 0, \text{ with } y(t=0) = y_0 \text{ and } y(t=t_{dr}) = 1$$

$$\tau_{Ndef} = \epsilon \epsilon_0 / e \mu N_{def}; \tau_m(t) = 2 \epsilon \epsilon_0 / e \mu m_0 (1 - \exp(-t/\tau_g)), m(t) = m_0 (1 - \exp(-t/\tau_g));$$

$$\tau_q(t) = \epsilon \epsilon_0 / \mu [q_0 \exp(-t/\tau_R) / d], q(t) = q_0 \exp(-t/\tau_R); t_{dr} \approx \tau_{dr} = d^2 / \mu U$$

$$j(t) \cong [q_0 \exp(-t/\tau_R) / \tau_{dr}] + [q_0 \exp(-t/\tau_R) / \tau_R] + [em_0 d \exp(-t/\tau_g) / 2 \tau_g].$$

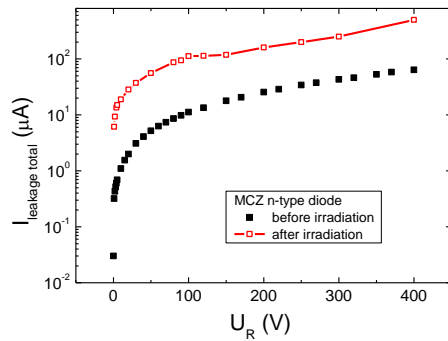
$$j(t) \approx [q_0 / \tau_{dr}], \text{ if } \tau_R \text{ \& } \tau_g \gg \tau_{dr}$$



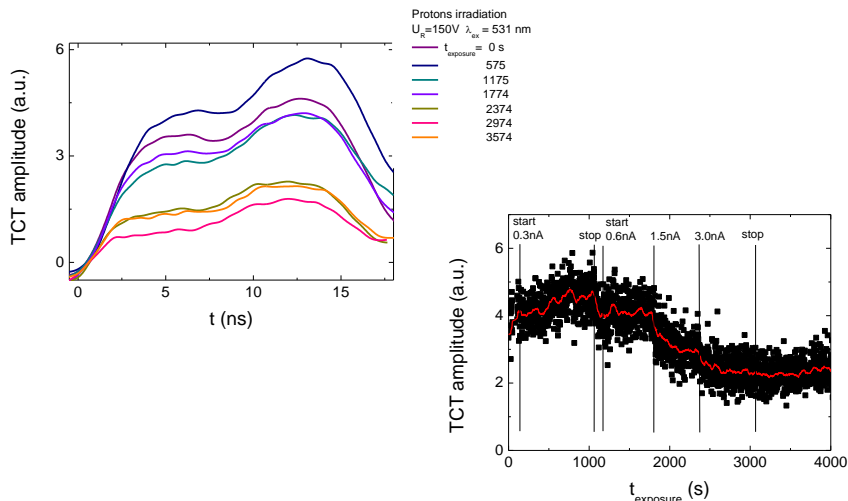
# Comparison of results of the on-line changes of the ICDC during 8 MeV proton beam and spallator 25 MeV neutrons irradiation

## 8 MeV protons

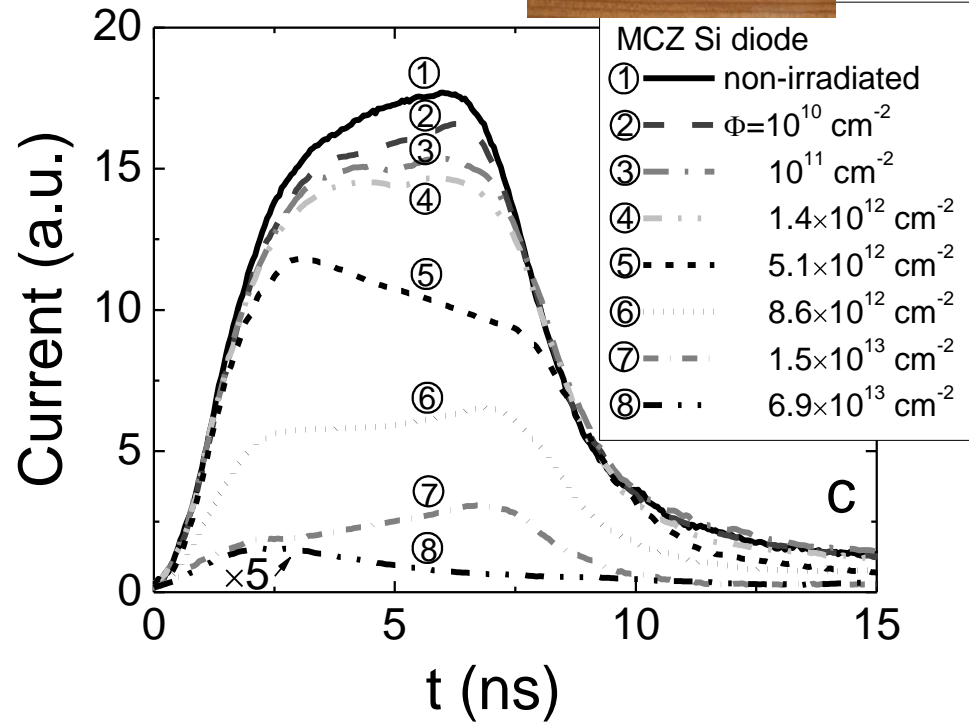
### Leakage current



### Induced charge current transients

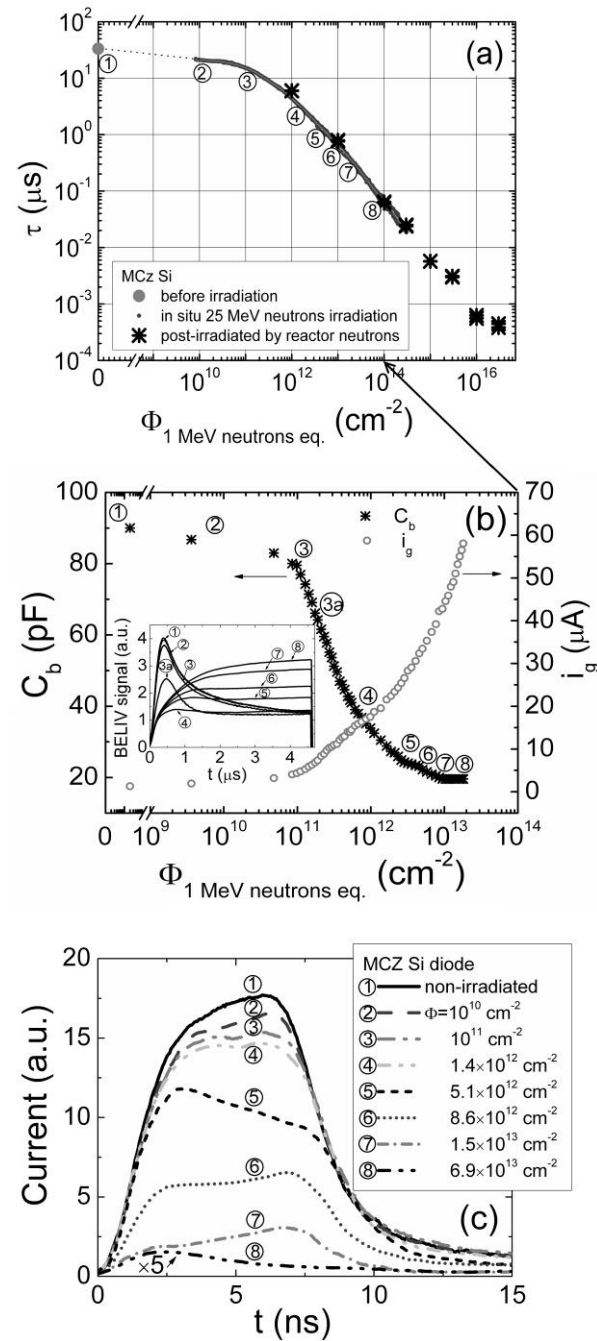
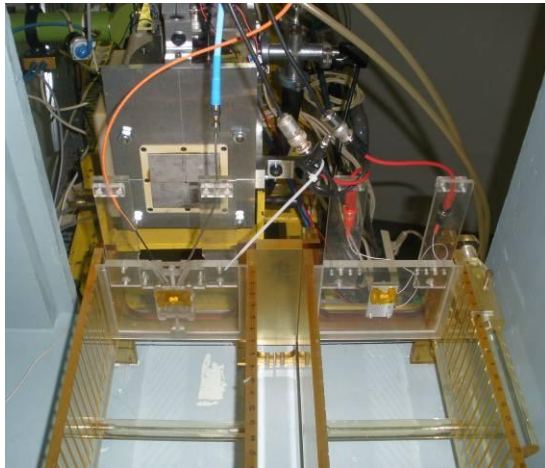
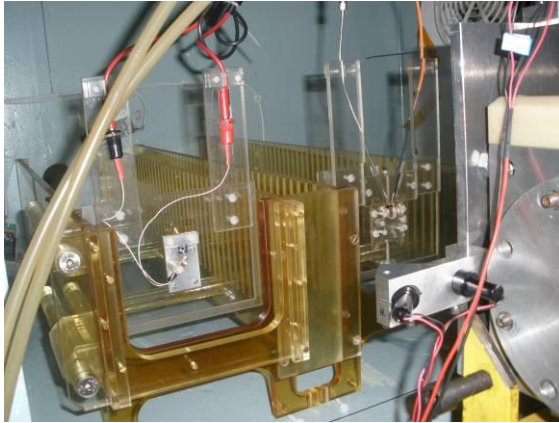


## Spallator neutrons



# Correlated evolution of the MW-PC, BELIV and ICDC characteristics during spallation neutrons irradiation:

transients registered every 10 ms, - more than  $10^5$  on each curve; irradiation - bunches of 4 ns duration



## Summary

•Spallator neutron irradiations are extremely useful for in situ experiments, as electrical noises are sufficiently small in comparison with those in proton beam chamber. On-line experiments are useful to predict detector behavior in operation regime.

•The observed changes of MW-PC, BELIV and ICDC transients well correlate mutually when considered relatively to an increasing fluence value. Thus, MW-PC correlated lifetime changes, measured in contact-less and distant manner, calibrated with other parameters is a powerful tool for examination in a wide dynamic range of carrier lifetimes, modified by radiation defects. Increased recombination rate in the heavily irradiated detectors may mask carrier drift. Thus, carrier recombination lifetime values, measured by MW-PC technique, can be employed in prediction of detector performance.

•Approach of carrier lifetime values to those of charge drift specific time scale leads to the non-operational junction. The observed increase of generation current within BELIV transients will cause a considerable increase of detector noise level.

## Acknowledgements.

Development of the employed measurement techniques and instrumentation have been supported by the Research Council of Lithuania, grant MIP-054/2011,

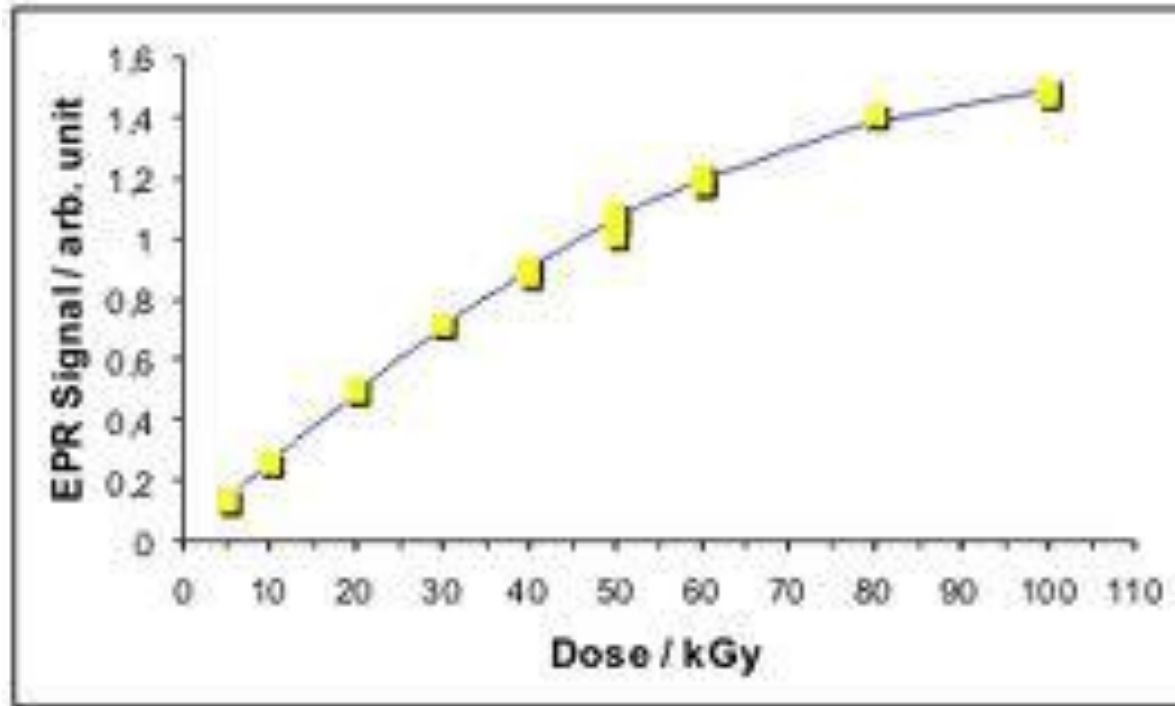
neutron irradiations were performed within frame of FP-7 “AIDA” project.

E.Tuominen, J.Harkonen, and J.Raisanen are appreciated for Si samples and detectors.

Thank You for attention!



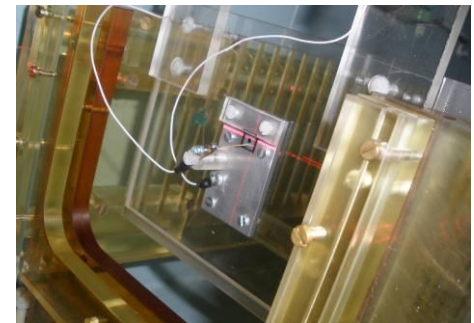
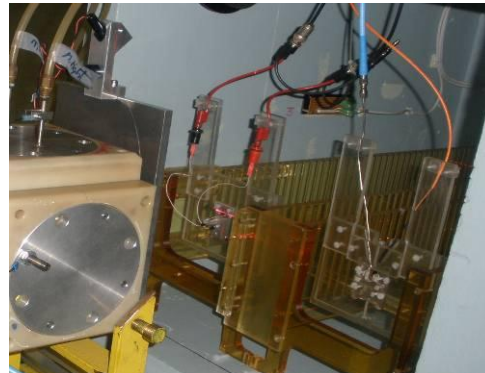
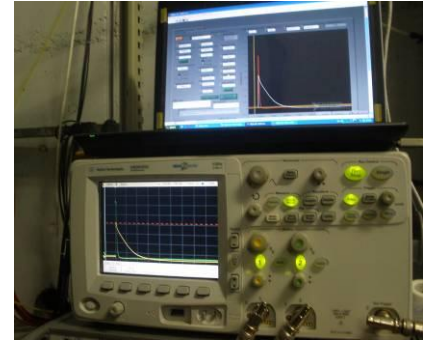
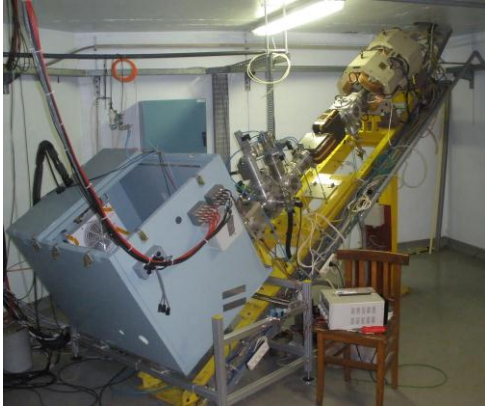
## Dosimetry using alanine [ $\text{CH}_3\text{CH}(\text{NH}_2)\text{COOH}$ –organic acid] EPR spectroscopy, - ESR of radiation created free radicals



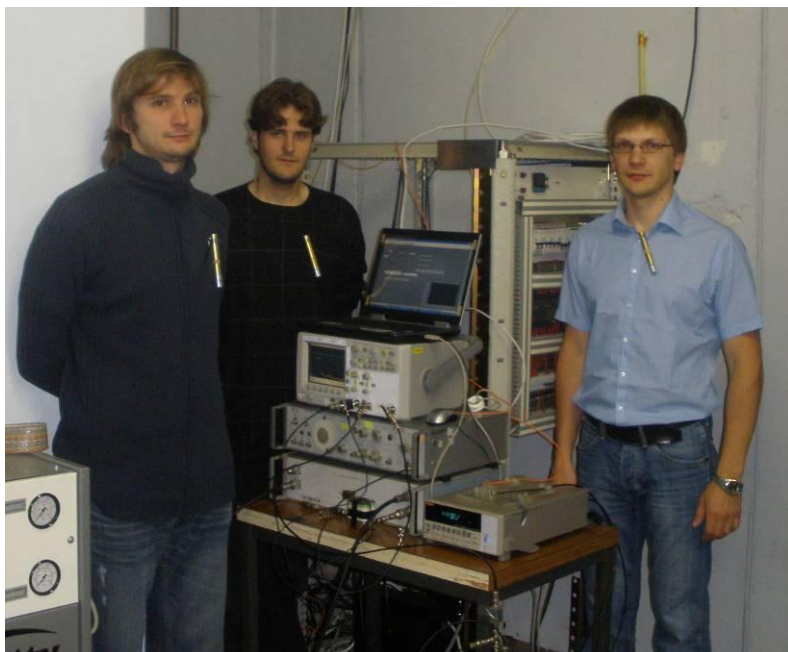
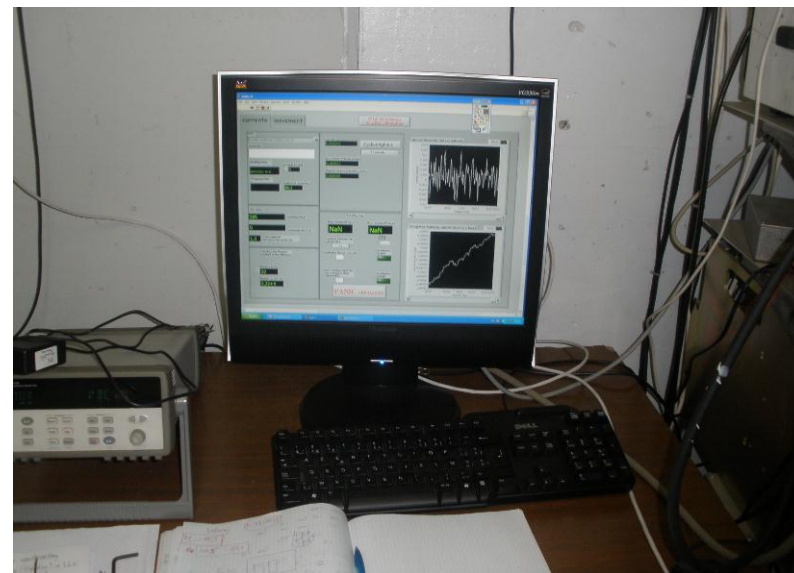
Dosimetry is based on the generation of the free radicals within the alanine pellets. Quantification of the radicals is implemented by detecting the free electrons using Electron Paramagnetic Resonance (EPR) Bruker spectrometer. Alanine dosimeter reader is calibrated to register doses between 0.05 kGy (corresponding to neutron fluence of  $10^{12}$  n/cm<sup>2</sup>) and 80 kGy (corresponding to neutron fluence of  $1.8 \times 10^{15}$  n/cm<sup>2</sup>).

# Sketch of experiments

The parallel on-line measurements of MW-PC, BELIV and ICDC characteristics have been performed keeping the same experimental conditions



## Sketch of experiments





# Neutron source at Louvain la Neuve University

Fluence  $\Phi$  (particles/cm<sup>2</sup>) is calculated from the integrated current, by the following formula:

$$\Phi(\text{particles/cm}^2) = \frac{10^{14} x I(\text{Integrated}, \mu A)}{0.079 x d^{1.902}}$$

Fluence (n/cm<sup>2</sup>) is directly proportional to  $I$ , integrated deuteron current (expressed in  $\mu A \times \text{hour}$ ), and inverse proportional to the distance  $d$  between the target and the sample (centimeters).

Alanine dosimeter reader is calibrated to read doses between 0.05 kGy (corresponding to neutron fluence of  $10^{12}$  n/cm<sup>2</sup>) and 80 kGy (corresponding to neutron fluence of  $1.8 \times 10^{15}$  n/cm<sup>2</sup>).

The hardness factor is defined as the ratio between the displacement damage cross-section for a specific particle energy distribution and the displacement damage cross-section of neutron of 1 MeV that has a known value of 95 MeV mb.

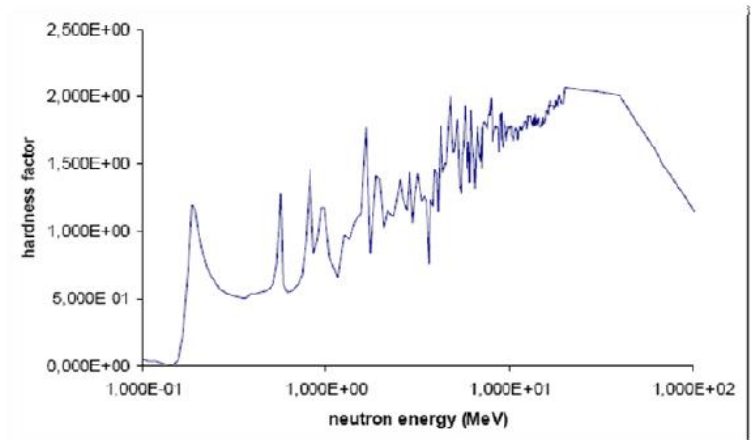
$$\Phi \text{ eq } \left( 1 \text{ MeV eq } \frac{\text{n}}{\text{cm}^2} \right) = K \Phi \left( \frac{\text{n}}{\text{cm}^2} \right)$$

$$K = \frac{D(E)}{95 \text{ MeV mb}} = \frac{\int_E \frac{d\phi(E) K(E) dE}{dE}}{\phi \text{ total}}$$

Calculation of the equivalence between neutron and proton irradiation and between absorbed dose (kGy) and fluence (1 MeV eq n/cm<sup>2</sup>)

Number of neutrons for several energy values and the total flux calculation

Energie moyenne pondérée (MeV)	Meulders et al. [42]	Période 1 (14/12/95)	Période 2 (13/03/96)	Période 3 (17/07/96)	Période 4 (06/09/96)
Flux absolu ( $10^{-16} \mu C^{-1} Sr^{-1}$ )					
4,91	0,115	0,1153	0,1154	0,1155	0,1154
8,68	0,126	0,1273	0,1273	0,1276	0,1274
14,91	0,194	0,1997	0,1997	0,2023	0,2003
22,78	0,297	0,3083	0,3082	0,3138	0,3089
31,22	0,102	0,103	0,103	0,1033	0,1031
39,09	0,024	0,024	0,024	0,024	0,024
45,32	0,0115	0,0115	0,0115	0,0115	0,0115
49,09	0,0068	0,0068	0,0068	0,0068	0,0068
Flux absolu total ( $10^{11} n \mu C^{-1} Sr^{-1}$ ) de 4 à 50 MeV					
5,8	6,0981	6,0979	6,1668	6,1086	
Flux absolu total moyen ( $10^{11} n \mu C^{-1} Sr^{-1}$ ) de 4 à 50 MeV					
6,12					



# Neutron source at Louvain la Neuve University

## Equivalence between fluence (particles/cm<sup>2</sup>) and dose (Gy)

To evaluate the correspondence between the neutron fluence and the absorbed dose in different materials (for our purpose: **silicon** and **alanine**) the KERMA values were used (sum of the kinetic energies of all the charged ionizing particles produced in the interactions: elastic scattering (n,n), inelastic scattering (n,n'γ), or (n,2n),(n,p),(n,α)...).

Neutrons absorbed dose (expressed in Gy) =  $\int \Phi(E)K(E)dE$  (integral over energy domain, 5 to 45 MeV);  $\Phi(E)$  is the energy distribution of the neutron beam,  $K(E)$  is the KERMA factor of the material expressed in fGy m<sup>2</sup>.

$$K = \frac{\int_0^{100} \varphi(E)K(E)dE}{\int_0^{100} \varphi(E)dE} = \frac{\int_0^{100} \varphi(E)K(E)dE}{\varphi \text{ total}}$$

The  $\Phi$  total as  $6.1 \times 10^{11}$  neutrons/ $\mu\text{C} \cdot \text{Sr}$ . The result of the integral considering the flux values and the KERMA factor is 1.52 fGy m<sup>2</sup>. Therefore for **Silicon**:

**Dose (Gy) = 1.52 (fGy m<sup>2</sup>) x  $\Phi$  (n/cm<sup>2</sup>).**

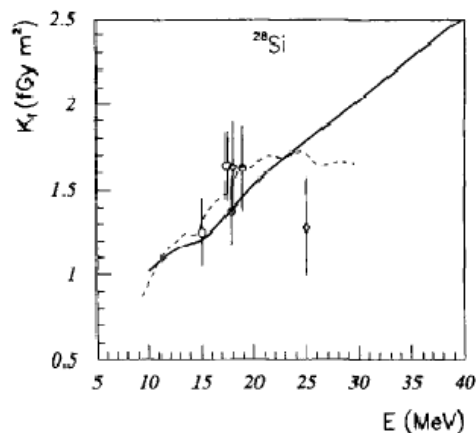


Fig. 12. Neutron kerma factor for silicon calculated with the ALICE code (solid line), with the measured (symbols) [3] and calculated (dashed line) results included.

Neutron kerma factor for H, C, O, N, Si (fGy m<sup>2</sup>)

E (MeV)	H	C	O	N	Si
15	48.1	2.06	1.31	1.5	1.21
20	47.0	3.10	1.85	2.04	1.53
25	45.85	3.41	2.08	2.46	1.74
30	44.51	3.64	2.37	2.78	2.02
40	42.92	4.0	3.0	3.62	2.51
50	40.75	4.39	3.67	4.44	3.08
60	39.04	4.97	4.4	5.24	3.62
70	37.72	5.49	4.96	5.9	4.16
80	36.74	6.03	5.6	6.58	4.73
90	36.05	6.69	6.3	7.2	5.33
100	35.58	7.54	6.94	8.0	5.86
120	35.23	9.03	8.35	9.34	6.93
150	35.82	11.05	10.2	11.34	8.48

Neutron kerma factors for composite materials (fGy m<sup>2</sup>)

E (MeV)	Tissue	CH	NaI	CsI	BaF <sub>2</sub>	CeF <sub>3</sub>	BGO	LS	PbWO <sub>4</sub>
15	6.12	5.6	0.08	0.02	0.46	0.62	0.20	0.36	0.18
20	6.55	6.45	0.21	0.08	0.52	0.69	0.36	0.50	0.27
25	6.66	6.67	0.35	0.16	0.59	0.78	0.44	0.58	0.33
30	6.78	6.75	0.47	0.25	0.68	0.89	0.56	0.69	0.41
40	7.16	6.99	0.77	0.47	0.91	1.15	0.83	0.94	0.62
50	7.52	7.19	1.08	0.72	1.21	1.49	1.13	1.23	0.85
60	7.98	7.59	1.40	0.99	1.50	1.82	1.44	1.54	1.11
70	8.35	7.97	1.72	1.24	1.82	2.18	1.72	1.82	1.35
80	8.82	8.39	2.02	1.49	2.11	2.51	2.01	2.12	1.59
90	9.37	8.95	2.29	1.72	2.38	2.80	2.26	2.40	1.82
100	9.93	9.70	2.57	1.94	2.66	3.12	2.54	2.70	2.06
120	11.2	11.0	3.15	2.42	3.28	3.79	3.12	3.32	2.58
150	12.9	13.0	3.97	3.08	4.08	4.68	3.95	4.16	3.28

### References

Data compilation of dosimetry methods and radiation sources for material testing, by M.Tavlet et al.

**CERN/TIS-CFM/IR/93-03, 1993.**

Calculations of the relative effectiveness of alanine for neutrons with energies up to 17.1 MeV, HM Getsenberg, **Rad.Prot.Dosimetry vol 31 N ¼ (85-89), 1990.**

Notes on fluence normalization based on the NIEL scaling hypothesis, A.Vasilescu and G.Lindstrom, **ROSE/TN/2000/02, 2000**

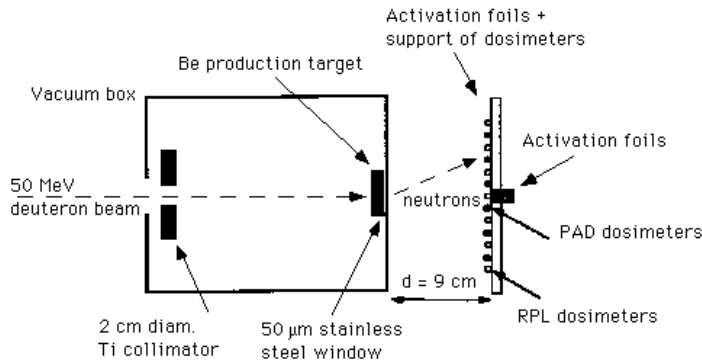
Neutron KERMA factors for tissue and particle detector materials from 15 to 150 MeV, D.

Gorbatkov, V. Kryuchkov, O. Sumaneev **NIM A 388 (1997) 260-266.**

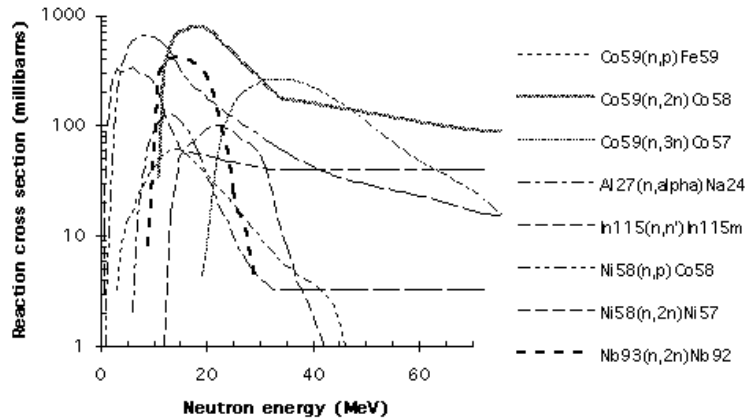
Updated NIEL calculations for estimating the damage induced by particles and gamma rays in Si and GaAs, A. Akkerman, J.Barak, M. Chadwick, J.Levinson, M.Murat, Y.Lifshitz **Radiation Physics and Chemistry 62 (2001) 301-310**

# Neutron source at Louvain la Neuve University

The deuteron beam has a time structure made of 4 nanosecond wide bunches with a repetition period of about 80 nanoseconds. This time structure is also reflected in the secondary neutron beam.



The absolute neutron flux is estimated from the activation [4] of several metallic foils through reactions (Table 1) of known cross-sections (Fig. 2) [5].

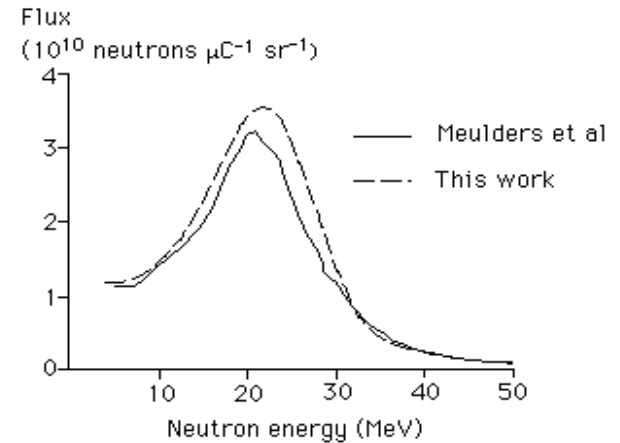


Particle type	Fraction	Average energy (MeV)	Maximum energy (MeV)
Neutron	1.0	20	50
Proton	$1.5 \cdot 10^{-4}$	12.61	25
Electron	$1.6 \cdot 10^{-4}$	1.57	6
Gamma	$2.4 \cdot 10^{-2}$	1.93	10

Beam contamination after the filter

Table 1: Production reactions, neutron energy range of sensitivity and half life [5] of the induced radioactive nuclei.

Reaction	Neutron energy range (MeV)	Half-life $T_{1/2}$
$^{115}\text{In} (n,\gamma) ^{116}\text{In}$	thermal	54.15 min
$^{115}\text{In} (n,n?) ^{115m}\text{In}$	1-14	4.49 h
$^{27}\text{Al} (n,\alpha) ^{24}\text{Na}$	7-27	14.96 h
$^{58}\text{Ni} (n,p) ^{58}\text{Co}$	2-20	70.916 d
$^{58}\text{Ni} (n,2n) ^{57}\text{Ni}$	12-40	1.5 d
$^{59}\text{Co} (n,\gamma) ^{60}\text{Co}$	thermal	5.27 y
$^{59}\text{Co} (n,p) ^{59}\text{Fe}$	4-30	44.5 d
$^{59}\text{Co} (n,2n) ^{58}\text{Co}$	14-50	70.916 d
$^{59}\text{Co} (n,3n) ^{57}\text{Co}$	>20	271.77 d
$^{93}\text{Nb} (n,2n) ^{92m}\text{Nb}$	9-30	10.15 d



The calculated production yield is  $6.6 \cdot 10^{11}$  neutrons  $\mu\text{C}^{-1} \text{sr}^{-1}$ . This is compatible with the one measured previously by Meulders et al. [7]. The maximum neutron flux achievable in this set-up, at a distance of 9 cm from the target, is  $7.3 \cdot 10^{10}$  neutrons  $\text{cm}^{-2} \text{s}^{-1}$ . It also means that a fluence equivalent to 10 years of LHC operation is reached in 23 minutes.

The measured dose rate using different methods:

- a calibrated ionization chamber mounted according to the ICRU-45 protocol [8] with a 20 cm thick polystyrene phantom. The tissue equivalent dose rate at the build-up is 28 cGy  $\mu\text{C}^{-1}$  with a relative error of 5 %;
- RPL (Radio Photo Luminescent) and PAD (Polymer Alanine Dosimeter) dosimeters provided and read by the TIS-TE group of CERN [5]. The values were comparable to the one measured with the ionization chamber.

The beam profile at 9 cm from the production target is evaluated using TLD's (Thermo Luminescent Dosimeter) (Fig. 4).

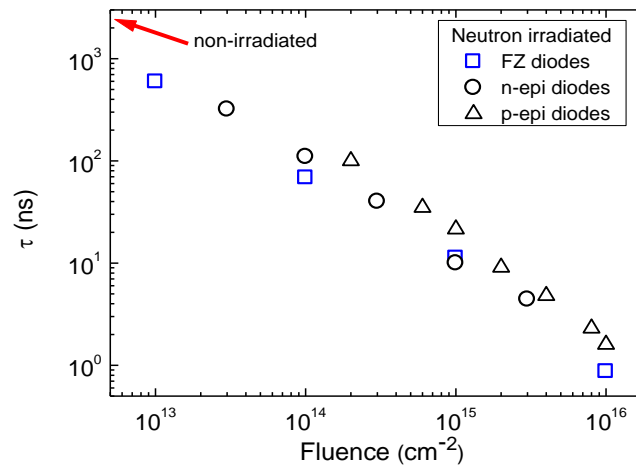
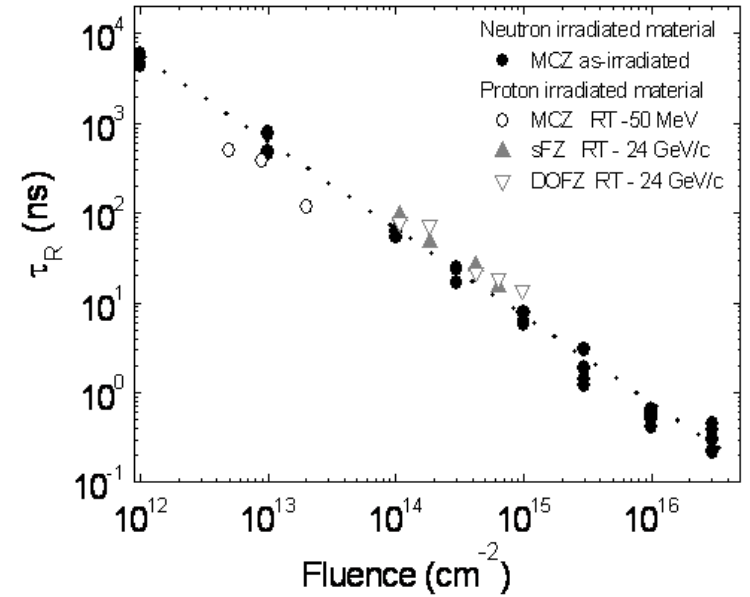
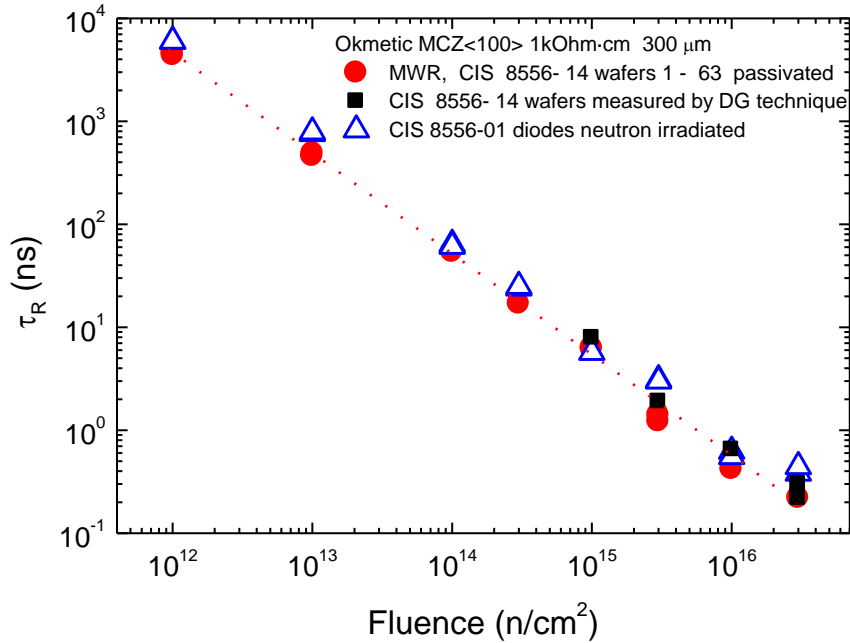
## An intense fast neutron beam in Louvain-la-Neuve

K. Bernier<sup>1</sup>, H. Boukhal<sup>2</sup>, J.-M. Denis<sup>3</sup>, T. El Bardouni<sup>2</sup>,

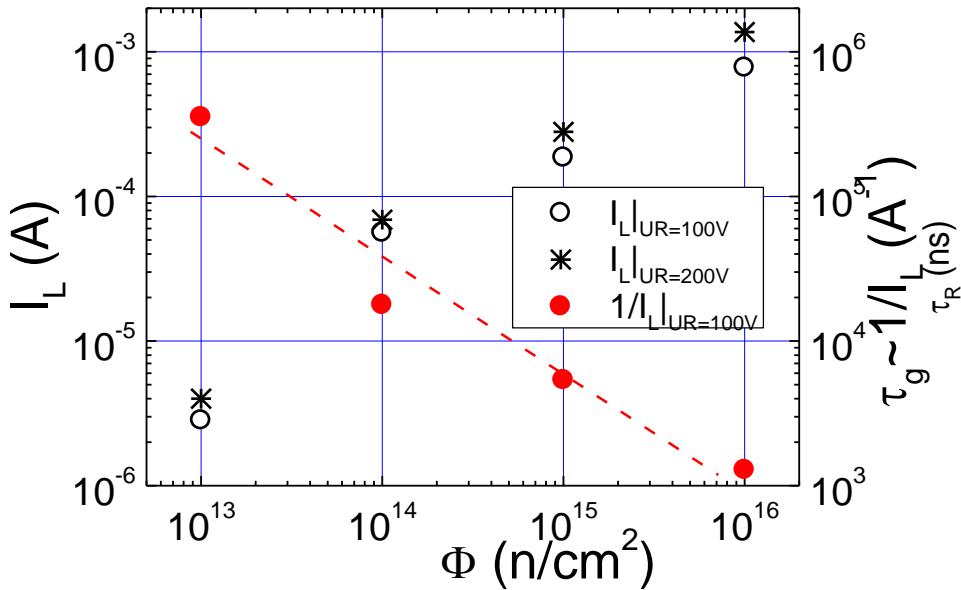
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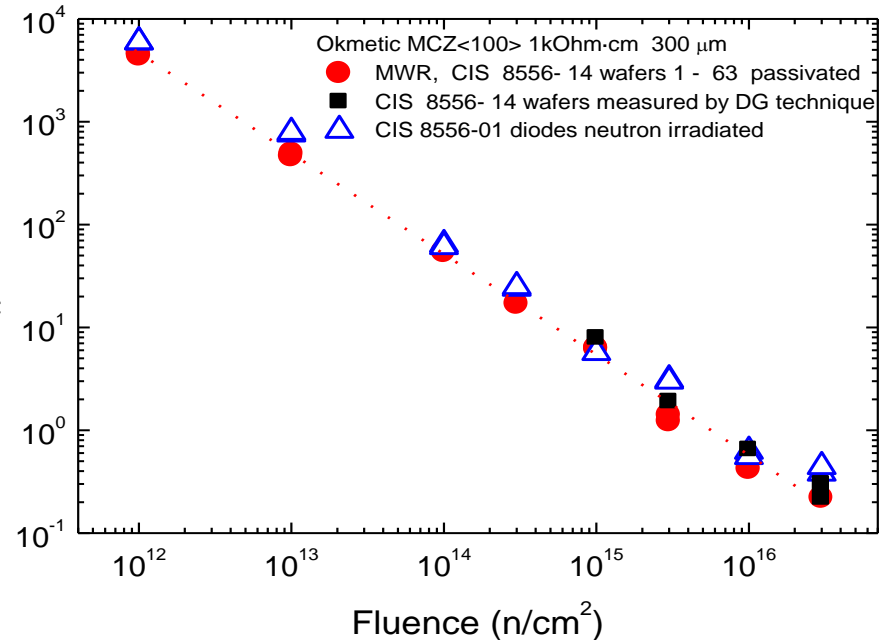
# Experience of VU team in monitoring of radiation impact on carrier recombination and generation lifetime control: Post-irradiation



# Carrier generation/emission and recombination lifetimes in Si detectors (for $M_{\text{rad}} \gg n_0$ )



Qualitative emission/ thermal generation lifetime dependence on fluence can be estimated from I-V's



Nearly linear reduction of generation lifetime with enhancement of fluence is similar to that of recombination lifetime characteristic

# Carrier recombination lifetimes (for $M \gg n_0$ )

Single-species (type) traps

$$\tau_p = \frac{\tau_{n0}(P_0 + P_{vM}) + \tau_{p0} \left[ n_0 + N_{cM} + M \left( 1 + \frac{n_0}{N_{cM}} \right)^{-1} \right]}{p_0 + n_0 + M \left( 1 + \frac{n_0}{N_{cM}} \right)^{-1} \left( 1 + \frac{N_{cM}}{n_0} \right)^{-1}}$$

$$\tau_n = \frac{\tau_{p0}(n_0 + N_{cM}) + \tau_{n0} \left[ p_0 + P_{vM} + M \left( 1 + \frac{p_0}{P_{vM}} \right)^{-1} \right]}{p_0 + n_0 + M \left( 1 + \frac{p_0}{P_{vM}} \right)^{-1} \left( 1 + \frac{P_{vM}}{p_0} \right)^{-1}}$$

$$m_0 = \frac{M}{e^{-\frac{-\Delta E_M - F}{kT}} + 1} = \frac{M}{\frac{N_{cM}}{n_0} + 1} = M - \frac{M}{\frac{P_{vM}}{p_0} + 1}$$

Although relaxation to equilibrium/steady-state is kept by  $M = p_M + n_M$

$M \rightarrow 0, \Delta n \rightarrow 0, S-R-H$

$$\tau = \tau_p = \tau_n = \tau_{p0} \frac{n_0 + N_{cM}}{n_0 + p_0} + \tau_{n0} \frac{p_0 + P_{vM}}{n_0 + p_0}$$

$M \rightarrow \infty, M \gg n_0, S-R-H$  invalid

$$\tau_p = \tau_{p0} \left( 1 + \frac{N_{cM}}{n_0} \right) = \frac{1}{\gamma_p m_0} = \tau_{p0}$$

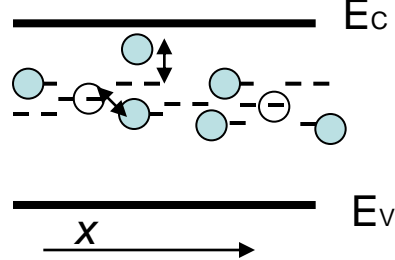
$$\tau_n = \tau_{n0} \left( 1 + \frac{P_{vM}}{p_0} \right) = \frac{1}{\gamma_n (M - m_0)} = \tau_{n0} = \frac{1}{\gamma_n M}$$

Capture coefficient  $\langle \gamma_n \rangle$  should be used instead of  $v\sigma$  within rigorous analysis

$$r = n \langle \gamma_n \rangle N_f P_h(E_f)$$

$$r = N_f P_h(E_f) \int_{E_c}^{\infty} \gamma(E) P_e(E) g_c(E) dE$$

$$\langle \gamma_n \rangle = \frac{\int_{E_c}^{\infty} \gamma(E) P_e(E) g_c(E) dE}{\int_{E_c}^{\infty} P_e(E) g_c(E) dE}$$



$$\tau_n \neq \tau_p$$

$$\tau_{rec} = \frac{1}{v\sigma M} = \frac{1}{\langle \gamma_n \rangle M}$$

$$\tau_{gen} = \frac{\exp(\frac{E_c - E_M}{kT})}{v\sigma N_c} = \frac{\exp(\frac{E_c - E_M}{kT})}{\langle \gamma \rangle N_c}$$

J.S. Blakemore, in: *Semiconductor Statistics*, Ch. 8, Pergamon Press, (1962)